

PATENT  
81790.0189

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of:

MOMOHARA, Tomomi

Serial No: 09/686,200 (reissue of U.S. Patent  
No. 5,818,249)

Filed: October 5, 2000

For: PROBE CARD HAVING GROUPS  
OF PROBE NEEDLES IN A  
PROBING TEST APPARATUS FOR  
TESTING SEMICONDUCTOR  
INTEGRATED CIRCUITS

Art Unit: 2829

Examiner: NGUYEN, Vinh P.

I hereby certify that this correspondence is being  
facsimile transmitted to the United States Patent  
and Trademark Office at (703) 872-9306, on:

December 24, 2003  
Date of Deposit

Michael Crapenhof, Reg. No. 37,115  
Name

*Michael Crapenhof* December 24, 2003  
Signature Date

**PETITION FOR EXTENSION OF TIME**

Commissioner for Patents  
Alexandria, VA 22313-1450

Dear Sir:

In accordance with 37 C.F.R. 1.136, Applicant respectfully petitions the  
Commissioner for a five-month extension of time extending to December 25, 2003,  
the period for response to the Office communication dated June 25, 2003.

Please charge the fee of \$2010.00 for this extension to Deposit Account  
No. 50-1314. The responsive papers are attached.

Please charge any insufficiency or credit any overpayment to Deposit Account  
No. 50-1314. A copy of this petition is enclosed.

Respectfully submitted,

HOGAN & HARTSON L.L.P.

By: *Michael Crapenhof*

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03/19/2004 RMISE1 00000001 501314 09686200  
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